

Data Sheet June 1999 File Number 1576.3

3.3A, 200V, 1.500 Ohm, N-Channel Power MOSFET

This N-Channel enhancement mode silicon gate power field effect transistor is an advanced power MOSFET designed, tested, and guaranteed to withstand a specified level of energy in the breakdown avalanche mode of operation. All of these power MOSFETs are designed for applications such as switching regulators, switching convertors, motor drivers, relay drivers, and drivers for high power bipolar switching transistors requiring high speed and low gate drive power. These types can be operated directly from integrated circuits.

Formerly developmental type TA17442.

Ordering Information

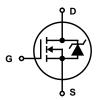
PART NUMBER	PACKAGE	BRAND				
IRF610	TO-220AB	IRF610				

NOTE: When ordering, use the entire part number.

Features

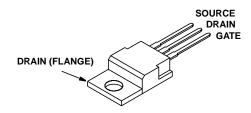
- 3.3A, 200V
- $r_{DS(ON)} = 1.500\Omega$
- Single Pulse Avalanche Energy Rated
- · SOA is Power Dissipation Limited
- · Nanosecond Switching Speeds
- · Linear Transfer Characteristics
- · High Input Impedance
- Related Literature
 - TB334 "Guidelines for Soldering Surface Mount Components to PC Boards"

Symbol



Packaging

JEDEC TO-220AB



Absolute Maximum Ratings $T_C = 25^{\circ}C$, Unless Otherwise Specified

	IRF610	UNITS
Drain to Source Voltage (Note 1)V _{DS}	200	V
Drain to Gate Voltage ($R_{GS} = 20k\Omega$) (Note 1)	200	V
Continuous Drain Current	3.3	Α
$T_C = 100^{\circ}C$	2.1	Α
Pulsed Drain Current (Note 2)	8	Α
Gate to Source Voltage	±20	V
Maximum Power Dissipation	43	W
Linear Derating Factor	0.34	W/oC
Single Pulse Avalanche Energy Rating (Note 4)	46	mJ
Operating and Storage Temperature	-55 to 150	οС
Maximum Temperature for Soldering		
Leads at 0.063in (1.6mm) from Case for 10sTL	300	οС
Package Body for 10s, See Techbrief 334	260	°C

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

1. $T_J = 25^{\circ}C$ to $125^{\circ}C$.

Electrical Specifications $T_C = 25^{\circ}C$, Unless Otherwise Specified

PARAMETER	SYMBOL	TEST CONDITIONS		MIN	TYP	MAX	UNITS
Drain to Source Breakdown Voltage	BV _{DSS}	$V_{GS} = 0V, I_D = 250\mu A \text{ (Figure 10)}$		200	-	-	V
Gate Threshold Voltage	V _{GS(TH)}	$V_{DS} = V_{GS}, I_{D} = 250\mu A$		2	-	4	V
Zero Gate Voltage Drain Current	I _{DSS}	V_{DS} = Max Rating, V_{GS} = 0V V_{DS} = Max Rating x 0.8, V_{GS} = 0V, T_J = 125°C		-	-	25	μΑ
				-	-	250	μΑ
On-State Drain Current (Note 2)	I _{D(ON)}	$V_{DS} > I_{D(ON)} \times r_{DS(ON)MAX}, V_{GS} = 10V$ (Figure 7)		3.3	-	-	Α
Gate to Source Leakage Current	I _{GSS}	$V_{GS} = \pm 20V$		-	-	±100	nA
Drain to Source On Resistance (Note 2)	r _{DS(ON)}	V _{GS} = 10V, I _D = 1.6A (Figures 8, 9)		-	1.0	1.5	Ω
Forward Transconductance (Note 2)	9fs	V _{DS} ≥ 50V, I _D = 1.6A (Figure 12)		0.8	1.3	-	S
Turn-On Delay Time	t _{d(ON)}	V_{DD} = 100V, I_D ≈ 3.3A, R_G = 24Ω, R_L = 30Ω MOSFET Switching Times are Essentially Independent of Operating		-	8	12	ns
Rise Time	t _r			=	17	26	ns
Turn-Off Delay Time	t _{d(OFF)}	Temperature	operating	-	13	21	ns
Fall Time	t _f			-	9	13	ns
Total Gate Charge (Gate to Source + Gate to Drain)	Q _{g(TOT)}	V_{GS} = 10V, I_D = 3.3A, V_{DS} = 0.8 x Rated BV _{DSS} , $I_{g(REF)}$ = 1.5mA (Figure 14) Gate Charge is Essentially Independent of Operating Temperature		-	5.3	8.2	nC
Gate to Source Charge	Q _{gs}			-	1.2	-	nC
Gate to Drain "Miller" Charge	Q _{gd}			-	3.0	-	nC
Input Capacitance	C _{ISS}	V _{GS} = 0V, V _{DS} = 25V, f = 1MHz (Figure 11)		-	135	-	pF
Output Capacitance	C _{OSS}			-	60	-	pF
Reverse Transfer Capacitance	C _{RSS}			-	16	-	pF
Internal Drain Inductance L _D	L _D	Measured From the Contact Screw on Tab to Center of Die	Modified MOSFET Symbol Showing the Internal Device Inductances	-	3.5	-	nH
		Measured From the Drain Lead, 6mm (0.25in) From Package to Center of Die		-	4.5	-	nH
Internal Source Inductance	L _S	Measured From the Source Lead, 6mm (0.25in) from Header to Source Bonding Pad		-	7.5	-	nH
Thermal Resistance Junction to Case	$R_{\theta JC}$			-	-	2.9	oC/W
Thermal Resistance Junction to Ambient	$R_{\theta JA}$	Free Air Operation		-	-	80	oC/W

Source to Drain Diode Specifications

PARAMETER	SYMBOL	TEST CONDITIONS		MIN	TYP	MAX	UNITS
Continuous Source to Drain Current	I _{SD}	Modified MOSFET Symbol	o D	-	-	3.3	Α
Pulse Source to Drain Current (Note 3)	ISDM	Showing the Integral Reverse P-N Junction Rectifier	GO	-	=	8	A
Source to Drain Diode Voltage (Note 2)	V_{SD}	$T_J = 25^{\circ}C$, $I_{SD} = 3.3A$, $V_{GS} = 0V$ (Figure 13)		-	-	2.0	V
Reverse Recovery Time	t _{rr}	$T_J = 25^{\circ}C$, $I_{SD} = 3.3A$, $dI_{SD}/dt = 100A/\mu s$		75	160	310	ns
Reverse Recovery Charge	Q _{RR}	$T_J = 25^{\circ}C$, $I_{SD} = 3.3A$, $dI_{SD}/dt = 100A/\mu s$		0.33	0.9	1.4	μС

NOTES:

- 2. Pulse test: pulse width $\leq 300 \mu s$, duty cycle $\leq 2\%$.
- 3. Repetitive rating: pulse width limited by maximum junction temperature. See Transient Thermal Impedance curve (Figure 3).
- 4. V_{DD} = 50V, starting T_J = 25°C, L = 6.4mH, R_G = 25 Ω , peak I_{AS} = 3.3A.

Typical Performance Curves Unless Otherwise Specified

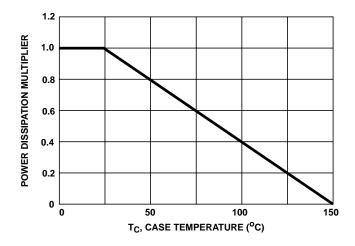


FIGURE 1. NORMALIZED POWER DISSIPATION vs CASE TEMPERATURE

FIGURE 2. MAXIMUM CONTINUOUS DRAIN CURRENT vs CASE TEMPERATURE

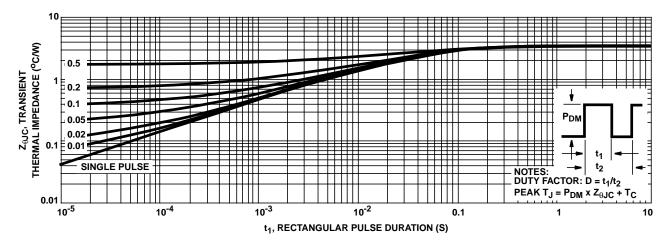


FIGURE 3. MAXIMUM TRANSIENT THERMAL IMPEDANCE

Typical Performance Curves Unless Otherwise Specified (Continued)

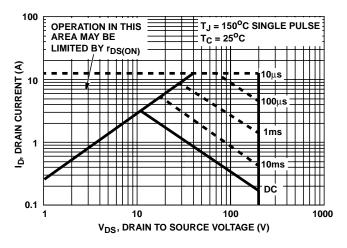


FIGURE 4. FORWARD BIAS SAFE OPERATING AREA

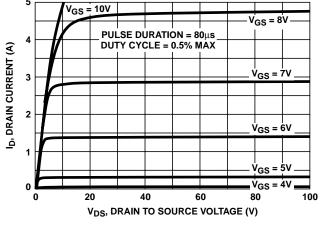


FIGURE 5. OUTPUT CHARACTERISTICS

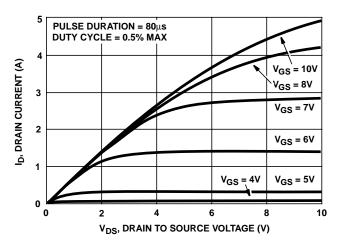


FIGURE 6. SATURATION CHARACTERISTICS

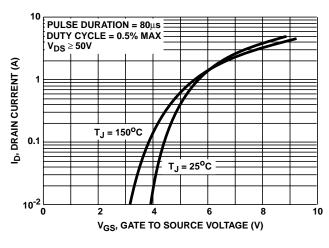


FIGURE 7. TRANSFER CHARACTERISTICS

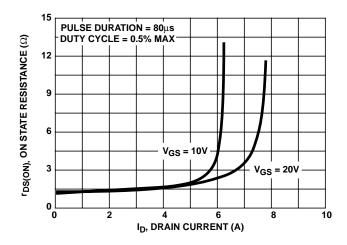


FIGURE 8. DRAIN TO SOURCE ON RESISTANCE vs GATE VOLTAGE AND DRAIN CURRENT

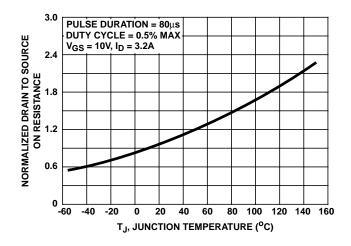


FIGURE 9. NORMALIZED DRAIN TO SOURCE ON RESISTANCE vs JUNCTION TEMPERATURE

Typical Performance Curves Unless Otherwise Specified (Continued)

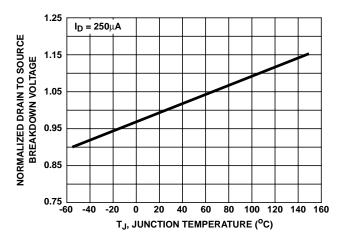


FIGURE 10. NORMALIZED DRAIN TO SOURCE BREAKDOWN VOLTAGE vs JUNCTION TEMPERATURE

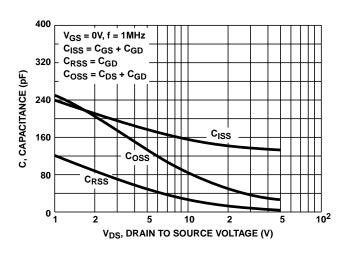


FIGURE 11. CAPACITANCE vs DRAIN TO SOURCE VOLTAGE

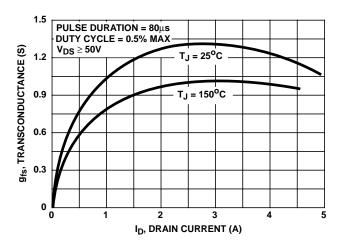


FIGURE 12. TRANSCONDUCTANCE vs DRAIN CURRENT

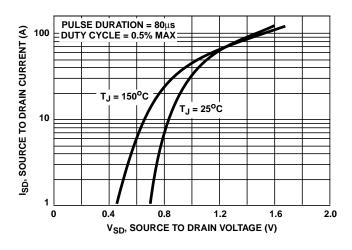


FIGURE 13. SOURCE TO DRAIN DIODE VOLTAGE

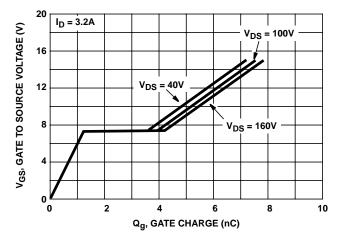


FIGURE 14. GATE TO SOURCE VOLTAGE vs GATE CHARGE

Test Circuits and Waveforms

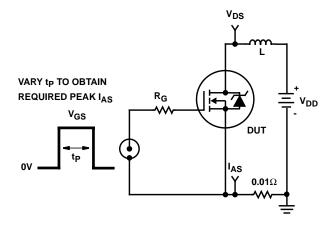


FIGURE 15. UNCLAMPED ENERGY TEST CIRCUIT

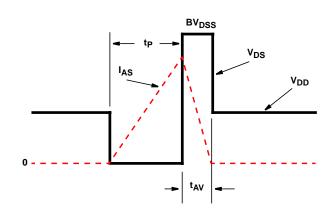


FIGURE 16. UNCLAMPED ENERGY WAVEFORMS

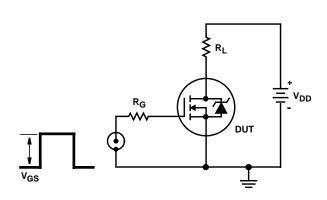


FIGURE 17. SWITCHING TIME TEST CIRCUIT

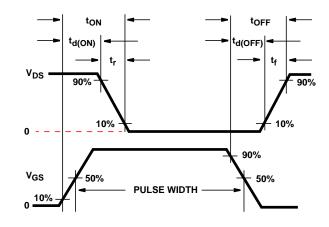


FIGURE 18. RESISTIVE SWITCHING WAVEFORMS

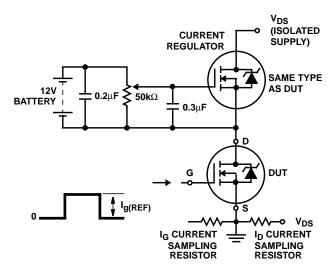


FIGURE 19. GATE CHARGE TEST CIRCUIT

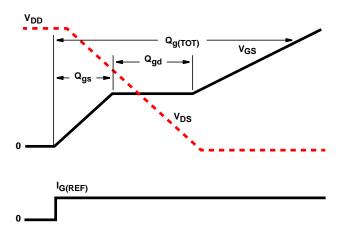


FIGURE 20. GATE CHARGE WAVEFORMS

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